RELIABILITY MONITOR

PROCESS: 2P, 1M, 0.8um,ThnEP/Si,ThnOx NdPdDSD,BPSG,N+ESD,1M/2M TiN,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS87C520	A15-	DEC '02	30255	0232	ATP (Amkor, PI)	DK241602AA	PLCC	500	75	0
DS87C520	A15-	DEC '02	30255	0232	ATP (Amkor, PI)	DK241602AA	PLCC	1000	75	0

TOTALS: **FAIL RATE (Fits): 13 DEVICE HRS: 7.07E+07 0**

RELIABILITY MONITOR

PROCESS: 1P, 2M, 0.8um, PdplDiode , WJ BPSG, N+ESD II,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1803	A2-	OCT '02	30229	0234	ATP (Amkor, PI)	DK236047AA	SOIC	500	80	0
DS1803	A2-	OCT '02	30229	0234	ATP (Amkor, PI)	DK236047AA	SOIC	1000	80	0

TOTALS: FAIL RATE (Fits): 12 DEVICE HRS: 7.55E+07 0

RELIABILITY MONITOR

PROCESS: D6W-1P2M,HPVt,E2,TCZ PBL:GOI

STRESS: HIGH TEMP OP LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1100	A3	JUL '03	31899	0323	NSEB	DJ330003ACC	SOIC	500	80	0
DS1100	A3	JUL '03	31899	0323	NSEB	DJ330003ACC	SOIC	1000	80	0

TOTALS: **FAIL RATE (Fits): 12 DEVICE HRS: 7.55E+07 0**

RELIABILITY MONITOR

PROCESS: D6RL-1P1M,SILP1,LLVt,N+ESD PBL:GOI

STRESS: HIGH TEMP OP LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS80C320	C5	SEP '03	32413	0323	ATEC	DQ338181AA	PDIP	500	77	0

TOTALS: FAIL RATE (Fits): 25 DEVICE HRS: 3.63E+07 0

RELIABILITY MONITOR

PROCESS: 1P, 1M, 0.6um, Pd, Ti/TiN M1 , WJ BPSG ,

STRESS: HIGH TEMP OP LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2401	C2	NOV '03	32947	0345	Hana	DU346103AF	TO92	500	80	0
DS2401	C2	FEB '04	33396	0403	Hana	DU349304AC	TO92	500	80	0
DS2401	C2	AUG '03	32237	0331	Hana	DU342603AB	TO92	500	80	0
DS2401	C2	AUG '03	32237	0331	Hana	DU342603AB	TO92	1000	80	0
DS2401	C2	NOV '03	32947	0345	Hana	DU346103AF	TO92	1000	80	0

TOTALS: FAIL RATE (Fits): 5 DEVICE HRS: 1.89E+08 0

RELIABILITY MONITOR

PROCESS: D6S-1P1M,HPVt,N+ESD,TCN3 ALOCOS:GOI

STRESS: HIGH TEMP OP LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2118M	C1-6	SEP '03	32420	0309	ATK (Amkor, K)	DN319658AA	SSOP	500	79	0

TOTALS: FAIL RATE (Fits): 25 DEVICE HRS: 3.73E+07 0

RELIABILITY MONITOR

PROCESS: D6S-1P1M,HPVt,N+ESD,TCN3 ALOCOS:GOI

STRESS: HIGH TEMP OP LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2118M	C1-6	SEP '03	32420	0309	ATK (Amkor, K)	DN319658AA	SSOP	500	79	0

TOTALS: FAIL RATE (Fits): 25 DEVICE HRS: 3.73E+07 0

RELIABILITY MONITOR

PROCESS: 1P, 1M, 0.8um, PdplDiode, Low Vts , N+ESDII, WJ BPSG,

STRESS: HIGH TEMP OP LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1232	C2-L	JUL '03	31906	0327	ATP (Amkor, PI)	DK343027AA	SOIC	500	80	0
DS1232	C2-L	JUL '03	31906	0327	ATP (Amkor, PI)	DK343027AA	SOIC	1000	80	0

TOTALS: **FAIL RATE (Fits): 12 DEVICE HRS: 7.55E+07 0**

RELIABILITY MONITOR

PROCESS: D8W-1P1M,HPVt,E2 LOCOS:GOI

STRESS: HIGH TEMP OP LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1620	D1	OCT '03	32504	0334	Hana	DU110113AA	SOIC	500	80	0
DS1620	D1	OCT '03	32504	0334	Hana	DU110113AA	SOIC	1000	80	0

TOTALS: **FAIL RATE (Fits): 12 DEVICE HRS: 7.55E+07 0**

RELIABILITY MONITOR

PROCESS: 1P, 1M, 1.2um, II Poly1 , TEOS Spacer,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1267	A1-5	OCT '03	32762	0340	ATP (Amkor, PI)	DK230310AC	TSSOP	500	80	0
DS1267	A1-5	OCT '03	32762	0340	ATP (Amkor, PI)	DK230310AC	TSSOP	1000	80	0

TOTALS: **FAIL RATE (Fits): 12 DEVICE HRS: 7.55E+07 0**